


<b>Search Notes</b> 	<b>Application/Control No.</b> 10821547	<b>Applicant(s)/Patent Under Reexamination</b> DIEDRICHSEN, STEFFAN
	<b>Examiner</b> HAI PHAN	<b>Art Unit</b> 2614

SEARCHED			
Class	Subclass	Date	Examiner
381	63, 64, 71.11	11/05/2009	HP
375	350, 343, 232	11/06/2009	HP
375	149-15, 232, 367	11/09/2009	HP
708	250, 271, 314, 322, 323, 420, 422, 425	11/09/2009	HP

SEARCH NOTES		
Search Notes	Date	Examiner
Inventor search	11/05/2009	HP
East search	11/05/2009	HP
PLUS Search	11/06/2009	HP
Consulted primary examiner Young Tse in Class 375 for fields of search	11/06/2009	HP
updated search	04/22/10	HP

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

/HAI PHAN/  
Examiner, Art Unit 2614